

<b>Notice of References Cited</b>	Application/Control No. 10/777,009	Applicant(s)/Patent Under Reexamination XU ET AL.	
	Examiner David L. Vanik	Art Unit 1615	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0124083	07-2003	Filipski et al.	424/73
	B	US-5,587,156	12-1996	Wdowik, Mark S.	424/73
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 02/87519	11-2002	WO Documnet	Dodd et al.	A61K 7/00
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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